

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. 12906 (YO9 58)	SERIAL NO. Unassigned
	APPLICANT(S) Eduard A. Cartier, et al.	
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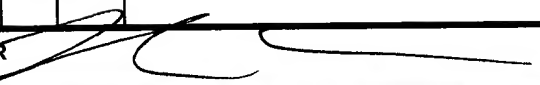
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>			
CC			Wilk, et al., "Electrical Properties of Hafnium Silicate Gate Dielectrics Deposited Directly on Silicon," Applied Physics Letters, Vol. 74, No. 19, pp. 2854-2856 (1999).

EXAMINER	DATE CONSIDERED 1-26-01
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LC		4,432,035	2/14/84	Hsieh et al.			
		5,190,888	3/2/93	Schwalke et al.			
		5,258,640	11/2/93	Hsieh et al.			
		5,541,131	7/30/96	Yoo et al.			
		5,554,560	9/10/96	Hsue et al.			
		5,672,898	9/30/97	Keller et al.			
		5,852,318	12/22/98	Chikamatsu et al.			
		5,876,788	3/2/99	Bronner et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
LC		Hubbard, et al., "Thermodynamic Stability of Binary Oxides in Contact With Silicon," J. Mater. Res., Vol. 11, No. 11, pp. 2757-2776 (1996).					
J		McKee, et al., "Crystalline Oxides on Silicon: The First Five Monolayers," Physical Review Letters, Vol. 81, No. 14, pp. 3014-3017 (1998).					
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